

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10044962	FUNAHASHI, TAKESHI
	Examiner	Art Unit
	Seth, Manav	2624

SEARCHED

Class	Subclass	Date	Examiner
382	128, 130,132, 232-253	3/27/2007	ms
378	5,37,105	3/27/2007	ms

SEARCH NOTES

Search Notes	Date	Examiner
East (Text and class) search - see attached search notes	3/27/2007	ms
IEEE Search	3/27/2007	ms
Inventor Search	3/27/2007	ms
STIC Plus Search	3/27/2007	ms
Interference Search - See attached search notes	3/27/2007	ms
Consulted Samir Ahmed (Primary Examiner)	3/27/2007	ms
Consulted Andy Johns (Primary Examiner)	2/17/2007	ms
Consulted Wenpeng Chen (Primary Examiner)	3/2/2007	ms

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	PGPUB Text Search - see attached search notes	3/27/2007	ms